

JPW

520.43279X00



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): S. YAMASHITA, et al
Serial No.: 10/706,972
Filed: November 14, 2003
For: QUALITY MONITORING SYSTEM FOR BUILDING
STRUCTURE, QUALITY MONITORING METHOD FOR
BUILDING STRUCTURE AND SEMICONDUCTOR
INTEGRATED CIRCUIT DEVICE
Group: 2857
Examiner:

INFORMATION DISCLOSURE STATEMENT
UNDER 37 CFR 1.97 & 1.98

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

October 7, 2004

Sir:

In the matter of the above-identified application, applicant(s) is/are submitting herewith a copy of the documents listed in the attached form equivalent to Form PTO-1449 for the Examiner's consideration.


This information disclosure statement is being submitted before the mailing date of a first office action on the merits.

To the extent that, the documents listed on the attached form equivalent to Form PTO-1449, are not in the English language, the requirement of 37 CFR 1.98(a)(3) for a concise explanation of the relevance is satisfied by an English language abstract.

It is respectfully requested that this information disclosure statement be considered by the Examiner.

Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account No. 01-2135 (520.43279X00) and please credit any excess fees to such deposit account.

Respectfully submitted,

A handwritten signature in black ink, appearing to read "Melvin Kraus", is written over a horizontal line.

Melvin Kraus

Registration No. 22,466

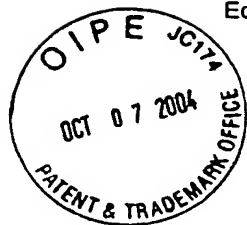
ANTONELLI, TERRY, STOUT & KRAUS, LLP

MK/cee
Attachments
(703) 312-6600

Form PTO-1449
Equivalent

U.S. Department of Commerce
Patent and Trademark Office

Atty. Docket No. 520.43279X00
Serial No. 10/706,972
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U.S. Patent Documents

Examiner Initials	Document No.	Date	Name	Class Subclass	Filing Date If Approp.
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Foreign Patent Documents

Document No.	Date	Country	Class Subclass	Translation Yes No
5-82890	11/93	Japan		(abstract)
8-082535	3/96	Japan		(abstract)

Other Documents (including Author, Title, Date, Pertinent Pages, etc.)

Examiner

Date Considered

*Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609;
Draw line through citation if not in conformance and not considered. Include copy of this form with next
communication to applicant.